

Figure 1 shows the number of concave defects of at least 0.3 μm as a function of etching depth for two different substrates, A and B. The data points are plotted for etching depths ranging from 0 to 2 μm. Substrate A (represented by circles) shows a high number of defects, peaking at approximately 50 defects at 0.5 μm etching depth. Substrate B (represented by triangles) shows a much lower number of defects, peaking at approximately 10 defects at 0.5 μm etching depth.

FIG.1

